

C0603X222K2GECTU

Aliases (C0603X222K2GEC7867)

ESD SMD Comm COG, Ceramic, 2,200 pF, 10%, 200 VDC, COG, SMD, MLCC, Temperature Stable, Electro Static Discharge, Class I, 0603, 0.4



General Information		
Series	ESD SMD Comm COG	
Style	SMD Chip	
Description	SMD, MLCC, Temperature Stable, Electro Static Discharge, Class I	
Features	Temperature Stable, Low ESR, Class I	
RoHS	Yes	
Termination	Flexible Termination	
Marking	No	
AEC-Q200	No	
Typical Component Weight	4.6 mg	
Shelf Life	78 Weeks	
MSL	1	

Dimensions	
Chip Size	0603
L	1.6mm +/-0.17mm
W	0.8mm +/-0.15mm
Т	0.8mm +/-0.15mm
S	0.4mm MIN
В	0.45mm +/-0.15mm

Packaging Specifications	
В	0.45mm +/-0.15mm
В	0.45
S	0.4mm MIN
Т	0.8mm +/-0.15mm

Specifications		
Capacitance	2,200 pF	
Measurement Condition	1 kHz 1.0Vrms	
Tolerance	10%	
Voltage DC	200 VDC	
ESD Level per AEC-Q200	12,000 V ESD Level	
Dielectric Withstanding Voltage	500 VDC	
Temperature Range	-55/+125°C	
Temp. Coefficient	COG	
Capacitance Change with Reference to +25°C and 0 VDC Applied (TCC)	30 ppm/C, 1kHz 1.0Vrms	
Dissipation Factor	0.1% 1 kHz 1.0Vrms	
Aging Rate	0% Loss/Decade Hour	
Insulation Resistance	100 GOhms	

Packaging	T&R, 180mm, Paper Tape	Capacitance Change with Reference to +25°C and 0 VDC Applied (TCC)	30 ppm/C, 1kHz 1.0Vrms
Packaging Quantity 4000	4000		
		Dissipation Factor	0.1% 1 kHz 1.0Vrms
		Aging Rate	0% Loss/Decade Hour
		Insulation Resistance	100 GOhms

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